

STGW40V60DLF, STGWT40V60DLF

600 V, 40 A very high speed
trench gate field-stop IGBT

Datasheet - production data

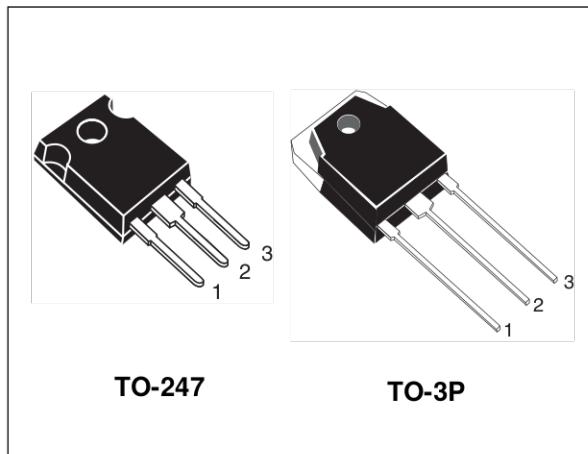
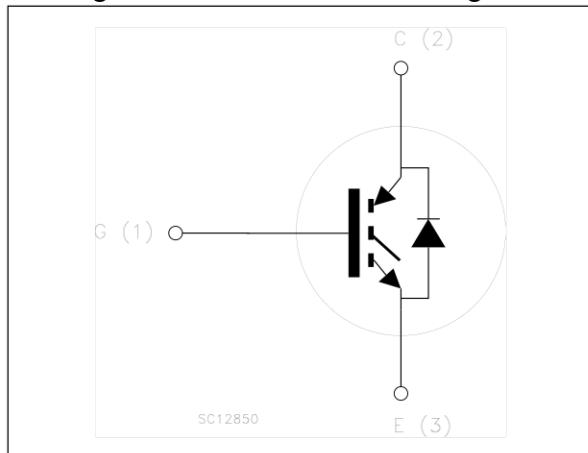


Figure 1. Internal schematic diagram



Features

- Designed for soft commutation only
- Maximum junction temperature: $T_J = 175^\circ\text{C}$
- Very high speed switching series
- Tail-less switching off
- Low saturation voltage: $V_{CE(\text{sat})} = 1.8 \text{ V (typ.)}$ @ $I_C = 40 \text{ A}$
- Tight parameters distribution
- Safe paralleling
- Low thermal resistance
- Low V_F soft recovery co-packaged diode
- Lead free package

Applications

- Induction heating
- Microwave oven
- Resonant converters

Description

This device is an IGBT developed using an advanced proprietary trench gate and field stop structure. The device is part of the "V" series of IGBTs, which represent an optimum compromise between conduction and switching losses to maximize the efficiency of very high frequency converters. Furthermore, a positive $V_{CE(\text{sat})}$ temperature coefficient and very tight parameter distribution result in safer paralleling operation.

Table 1. Device summary

Order code	Marking	Package	Packaging
STGW40V60DLF	GW40V60DLF	TO-247	Tube
STGWT40V60DLF	GWT40V60DLF	TO-3P	Tube

Contents

1	Electrical ratings	3
2	Electrical characteristics	4
2.1	Electrical characteristics (curves)	6
3	Test circuits	11
4	Package mechanical data	12
5	Revision history	16

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{CES}	Collector-emitter voltage ($V_{GE} = 0$)	600	V
I_C	Continuous collector current at $T_C = 25^\circ\text{C}$	80	A
I_C	Continuous collector current at $T_C = 100^\circ\text{C}$	40	A
$I_{CP}^{(1)}$	Pulsed collector current	160	A
V_{GE}	Gate-emitter voltage	± 20	V
I_F	Continuous forward current at $T_C = 25^\circ\text{C}$	80	A
I_F	Continuous forward current at $T_C = 100^\circ\text{C}$	40	A
$I_{FP}^{(1)}$	Pulsed forward current	160	A
P_{TOT}	Total dissipation at $T_C = 25^\circ\text{C}$	283	W
T_{STG}	Storage temperature range	- 55 to 150	$^\circ\text{C}$
T_J	Operating junction temperature	- 55 to 175	$^\circ\text{C}$

1. Pulse width limited by maximum junction temperature and turn-off within RBSOA

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R_{thJC}	Thermal resistance junction-case IGBT	0.53	$^\circ\text{C}/\text{W}$
R_{thJC}	Thermal resistance junction-case diode	1.4	$^\circ\text{C}/\text{W}$
R_{thJA}	Thermal resistance junction-ambient	50	$^\circ\text{C}/\text{W}$

2 Electrical characteristics

$T_J = 25^\circ\text{C}$ unless otherwise specified.

Table 4. Static characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{CES}}$	Collector-emitter breakdown voltage ($V_{GE} = 0$)	$I_C = 2 \text{ mA}$	600			V
$V_{CE(\text{sat})}$	Collector-emitter saturation voltage	$V_{GE} = 15 \text{ V}, I_C = 40 \text{ A}$		1.8	2.3	V
		$V_{GE} = 15 \text{ V}, I_C = 40 \text{ A}$ $T_J = 125^\circ\text{C}$		2.15		
		$V_{GE} = 15 \text{ V}, I_C = 40 \text{ A}$ $T_J = 175^\circ\text{C}$		2.35		
V_F	Forward on-voltage	$I_F = 40 \text{ A}$		1.55	1.8	V
		$I_F = 40 \text{ A}$ $T_J = 125^\circ\text{C}$		1.3		V
		$I_F = 40 \text{ A}$ $T_J = 175^\circ\text{C}$		1.25		V
$V_{GE(\text{th})}$	Gate threshold voltage	$V_{CE} = V_{GE}, I_C = 1 \text{ mA}$	5	6	7	V
I_{CES}	Collector cut-off current ($V_{GE} = 0$)	$V_{CE} = 600 \text{ V}$			25	μA
I_{GES}	Gate-emitter leakage current ($V_{CE} = 0$)	$V_{GE} = \pm 20 \text{ V}$			250	nA

Table 5. Dynamic characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{ies}	Input capacitance	$V_{CE} = 25 \text{ V}, f = 1 \text{ MHz},$ $V_{GE} = 0$	-	5400	-	pF
C_{oes}	Output capacitance		-	220	-	pF
C_{res}	Reverse transfer capacitance		-	180	-	pF
Q_g	Total gate charge	$V_{CC} = 480 \text{ V}, I_C = 40 \text{ A},$ $V_{GE} = 15 \text{ V}$ (see Figure 27)	-	226	-	nC
Q_{ge}	Gate-emitter charge		-	38	-	nC
Q_{gc}	Gate-collector charge		-	95	-	nC

Table 6. IGBT switching characteristics (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(\text{off})}$	Turn-off delay time	$V_{CE} = 400 \text{ V}, I_C = 40 \text{ A}, R_G = 10 \Omega, V_{GE} = 15 \text{ V}$ (see Figure 25)		208		ns
t_f	Current fall time		-	20	-	ns
$E_{\text{off}}^{(1)}$	Turn-off switching losses		-	411	-	μJ
$t_{d(\text{off})}$	Turn-off delay time	$V_{CE} = 400 \text{ V}, I_C = 40 \text{ A}, R_G = 10 \Omega, V_{GE} = 15 \text{ V}, T_J = 175 \text{ }^\circ\text{C}$ (see Figure 25)		220		ns
t_f	Current fall time		-	21	-	ns
$E_{\text{off}}^{(1)}$	Turn-off switching losses		-	560	-	μJ

1. Turn-off losses include also the tail of the collector current.

Table 7. IGBT switching characteristics (capacitive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$E_{\text{off}}^{(1)}$	Turn-off switching losses	$V_{CC} = 320 \text{ V}, R_G = 10 \Omega, I_C = 40 \text{ A}, L = 100 \mu\text{H}, C_{\text{sstab}} = 20 \text{ nF}$ (see Figure 26)	-	147	-	μJ
		$V_{CC} = 320 \text{ V}, R_G = 10 \Omega, I_C = 40 \text{ A}, L = 100 \mu\text{H}, C_{\text{sstab}} = 20 \text{ nF}, T_J = 175 \text{ }^\circ\text{C}$ (see Figure 26)	-	303	-	

1. Turn-off losses include also the tail of the collector current.

2.1 Electrical characteristics (curves)

Figure 2. Power dissipation vs. case temperature

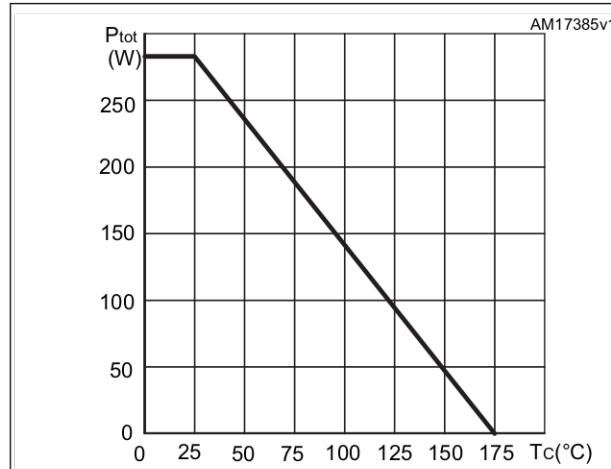


Figure 3. Collector current vs. case temperature

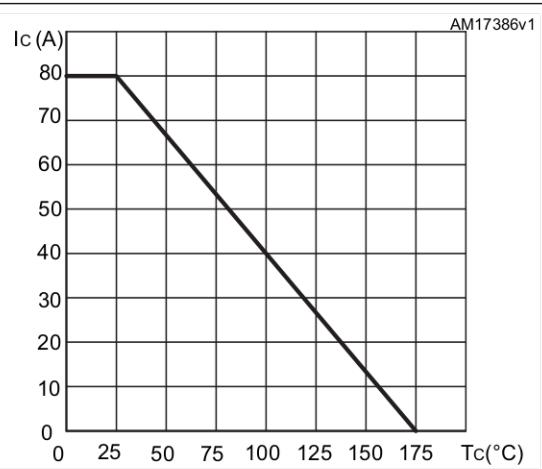


Figure 4. Output characteristics ($T_j=25^\circ\text{C}$)

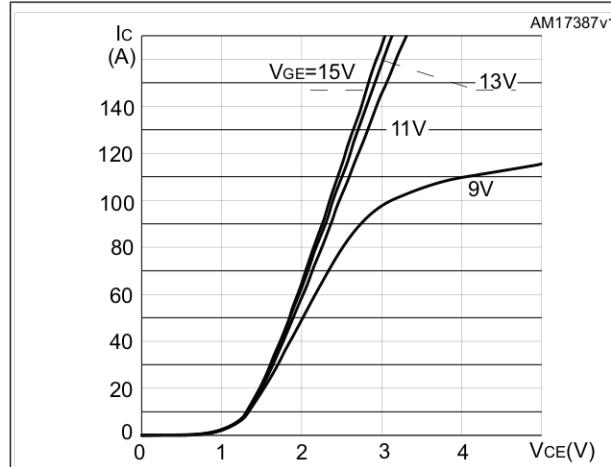


Figure 5. Output characteristics ($T_j=175^\circ\text{C}$)

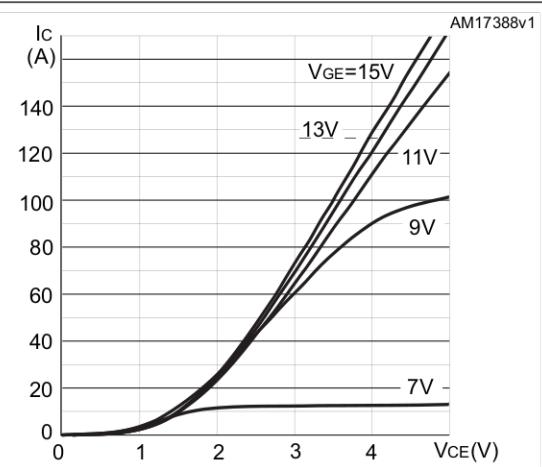


Figure 6. $V_{CE(\text{sat})}$ vs. junction temperature

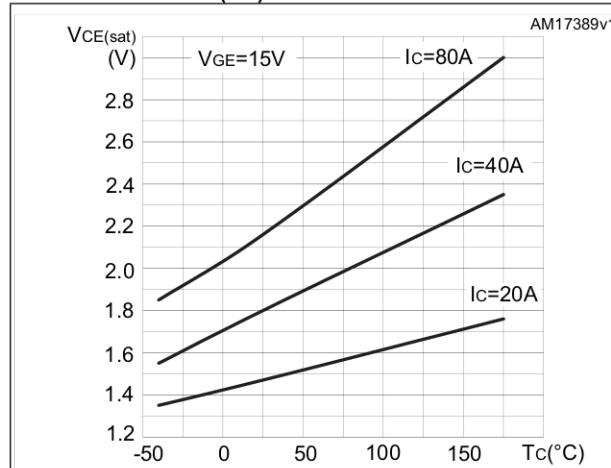


Figure 7. $V_{CE(\text{sat})}$ vs. collector current

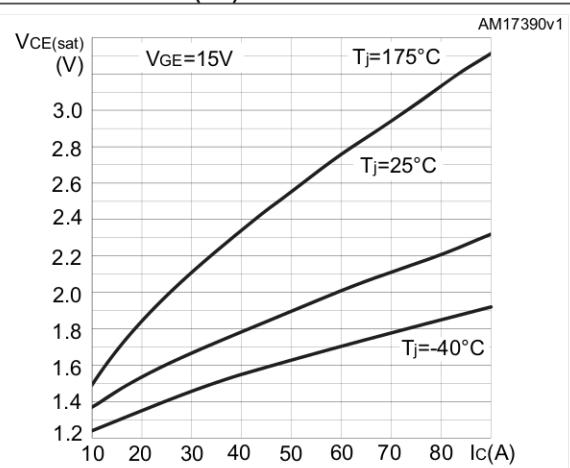


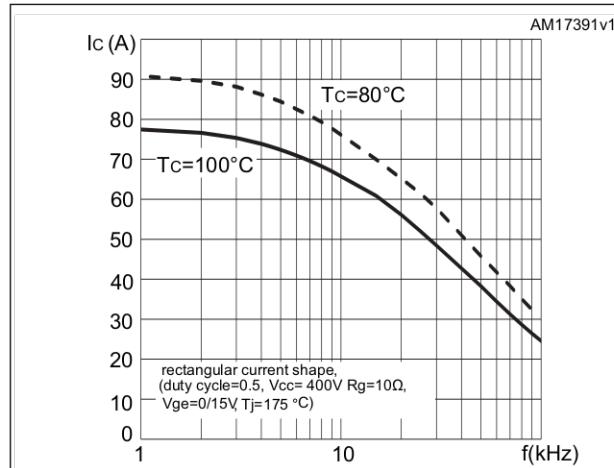
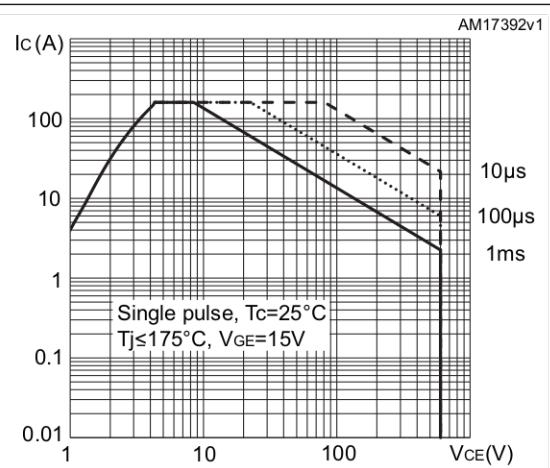
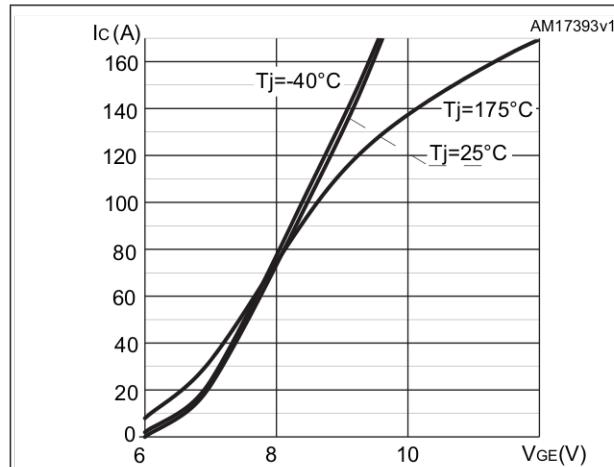
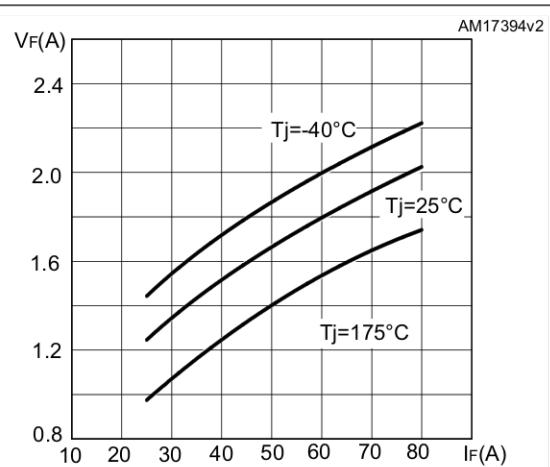
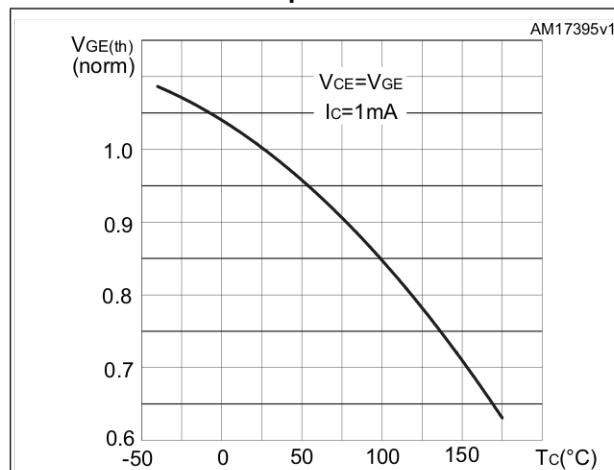
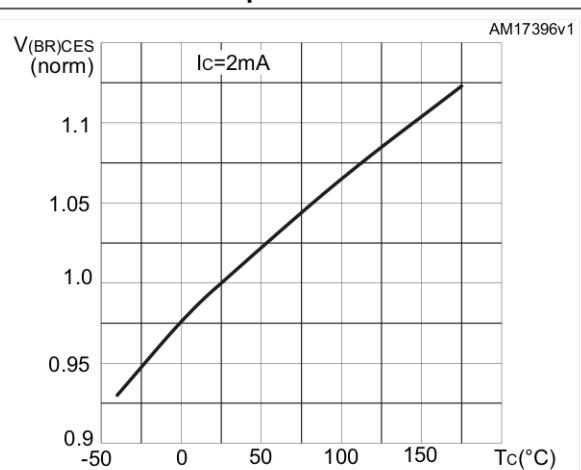
Figure 8. Collector current vs. switching frequency**Figure 9. Forward bias safe operating area****Figure 10. Transfer characteristics****Figure 11. Diode V_F vs. forward current****Figure 12. Normalized V_{GE(th)} vs junction temperature****Figure 13. Normalized V_{(BR)CES} vs. junction temperature**

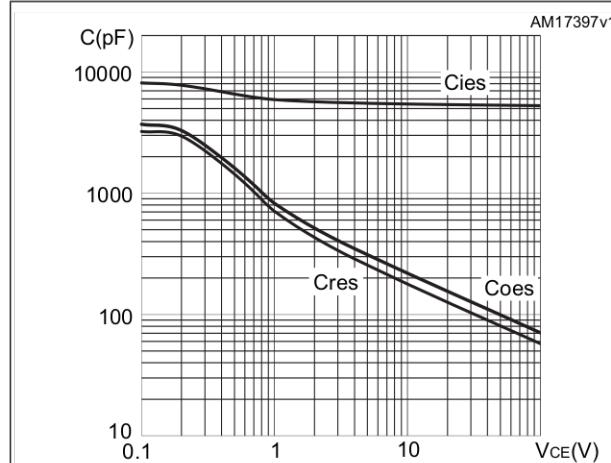
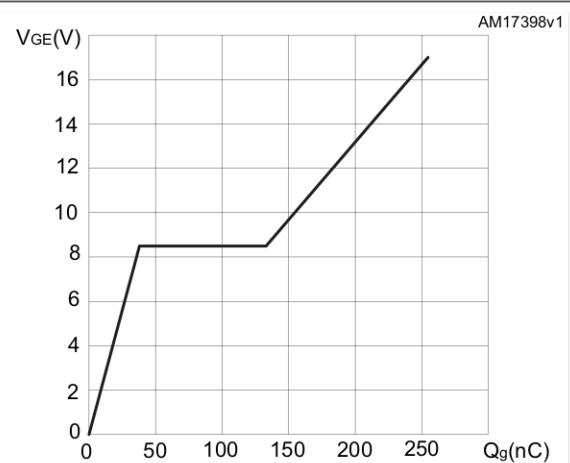
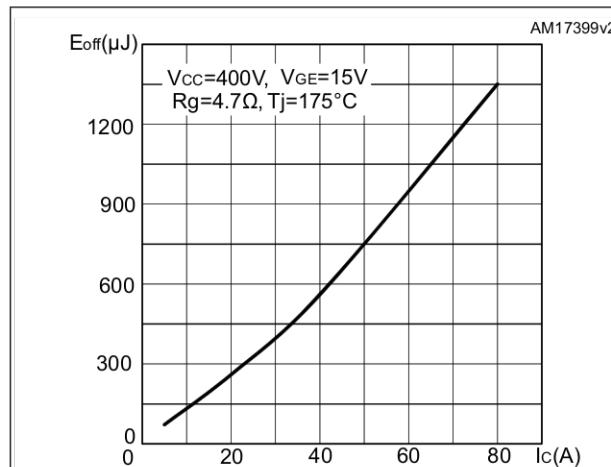
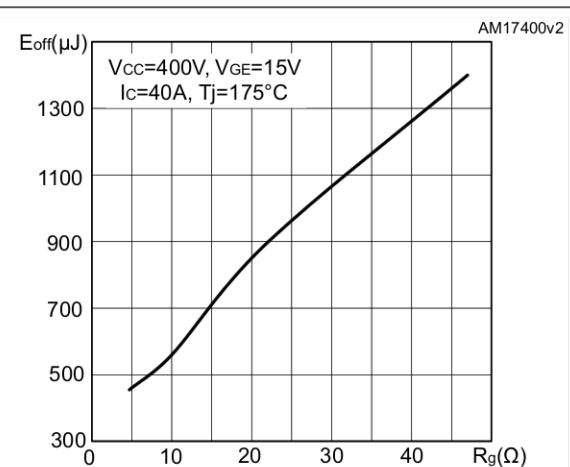
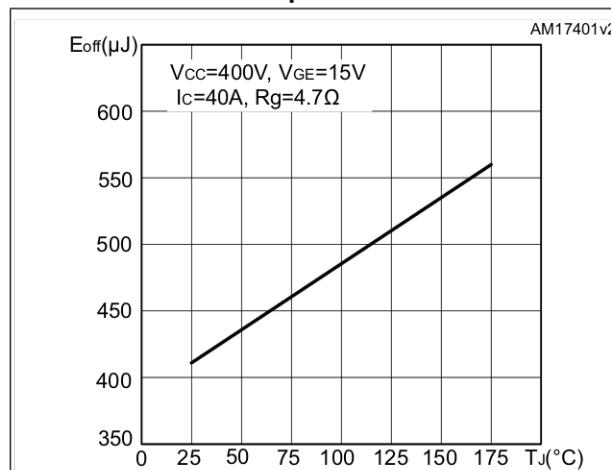
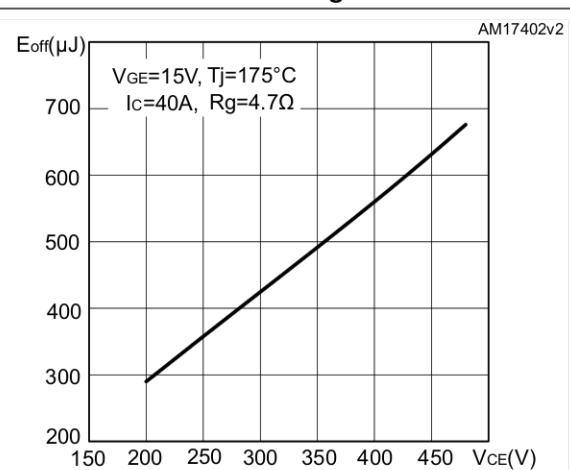
Figure 14. Capacitance variations**Figure 15. Gate charge vs. gate-emitter voltage****Figure 16. Switching-off losses vs. collector current****Figure 17. Switching-off losses vs. gate resistance****Figure 18. Switching-off losses vs. junction temperature****Figure 19. Switching-off losses vs. collector-emitter voltage**

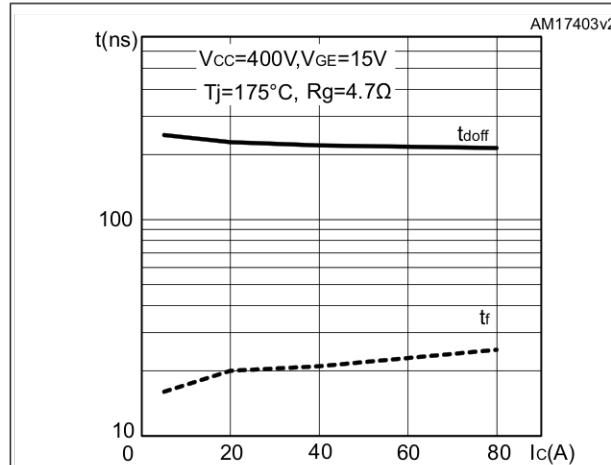
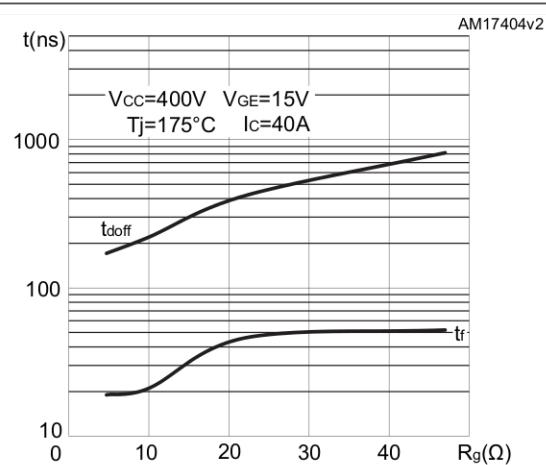
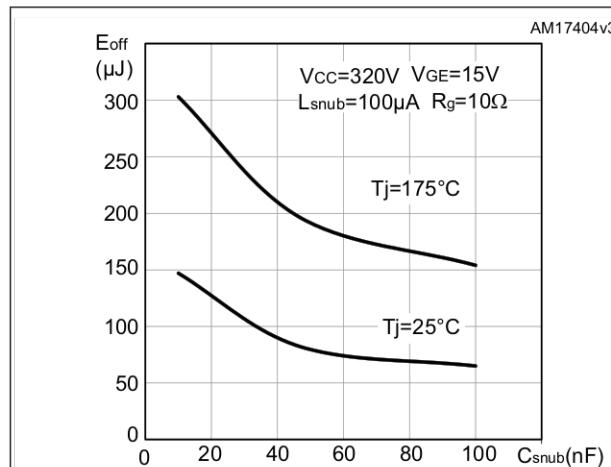
Figure 20. Switching times vs. collector current**Figure 21. Switching times vs. gate resistance****Figure 22. Switching-off losses vs. capacitive load**

Figure 23. Thermal data for IGBT

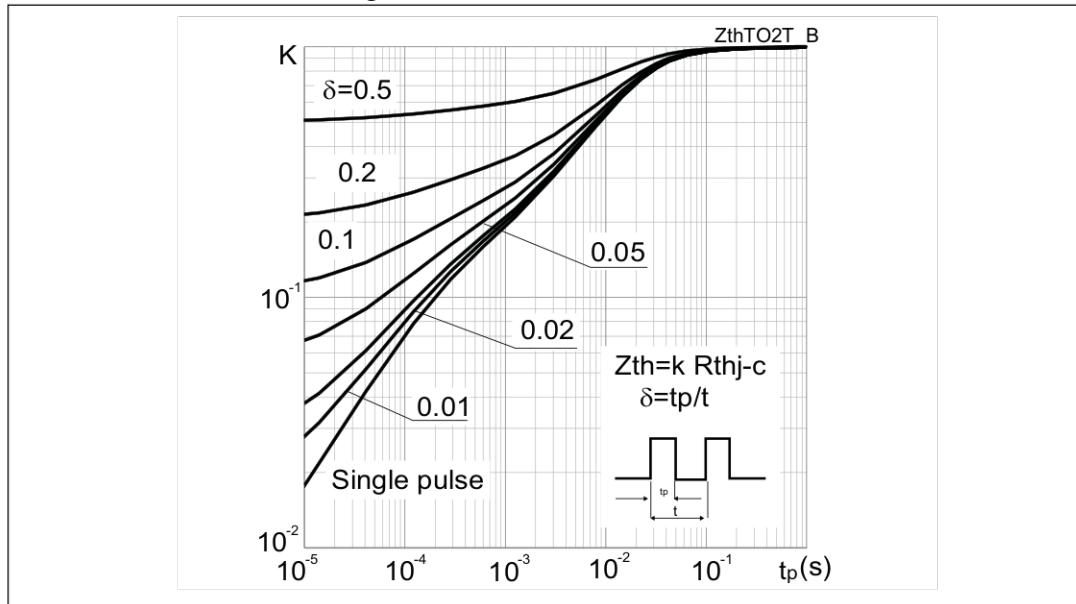
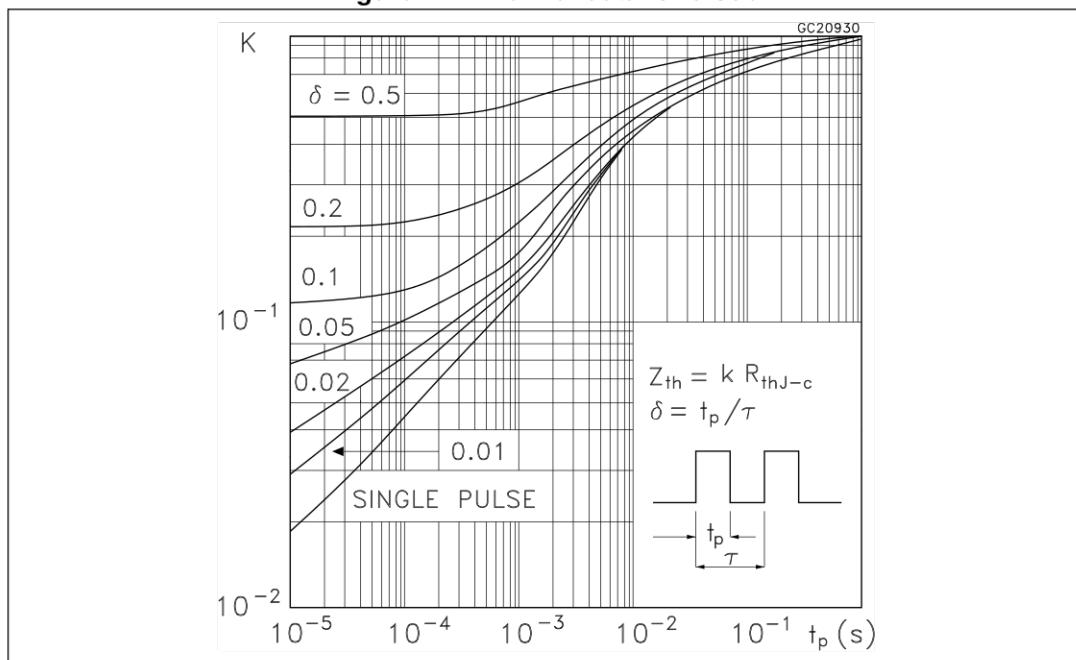


Figure 24. Thermal data for diode



3 Test circuits

Figure 25. Test circuit for inductive load switching

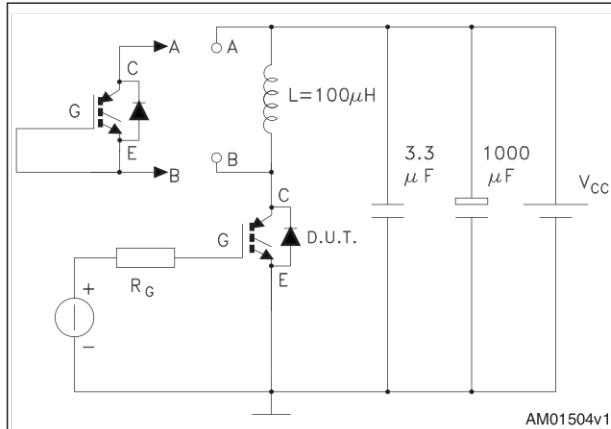


Figure 26. Test circuit for capacitive load switching

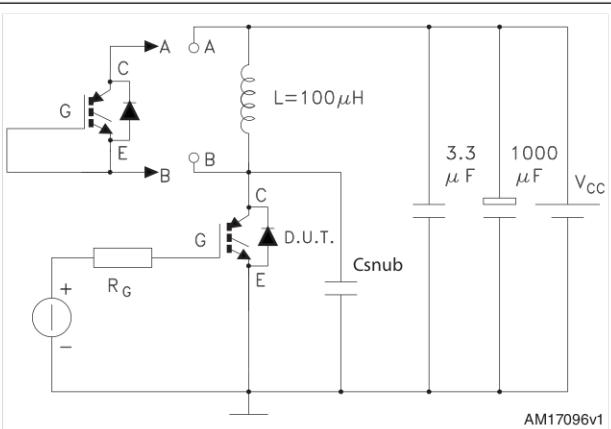


Figure 27. Gate charge test circuit

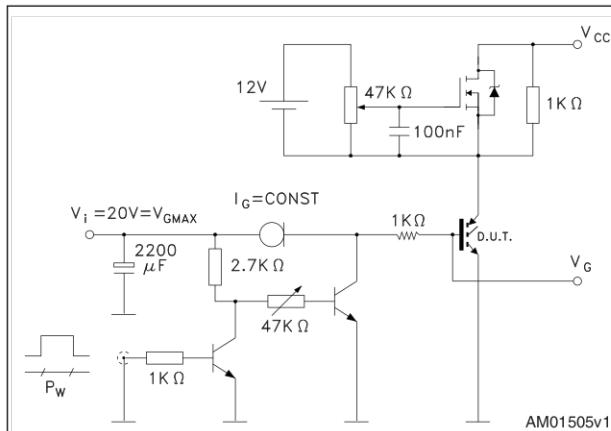


Figure 28. Switching waveform

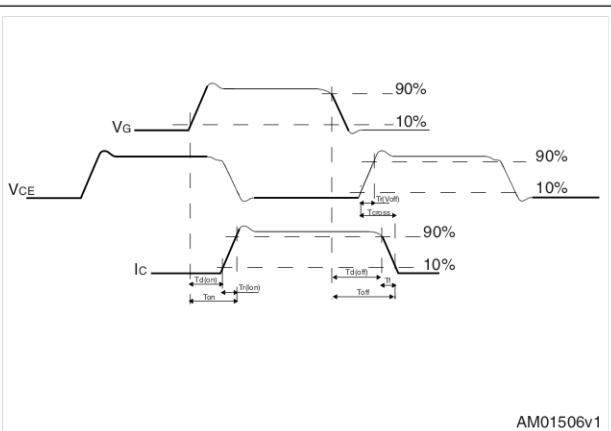
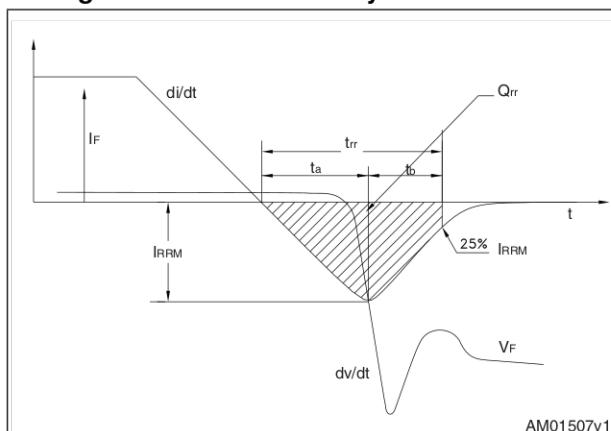


Figure 29. Diode recovery time waveform



4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com.
ECOPACK is an ST trademark.

Table 8. TO-247 mechanical data

Dim.	mm.		
	Min.	Typ.	Max.
A	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
c	0.40		0.80
D	19.85		20.15
E	15.45		15.75
e	5.30	5.45	5.60
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
ØP	3.55		3.65
ØR	4.50		5.50
S	5.30	5.50	5.70

Figure 30. TO-247 drawing

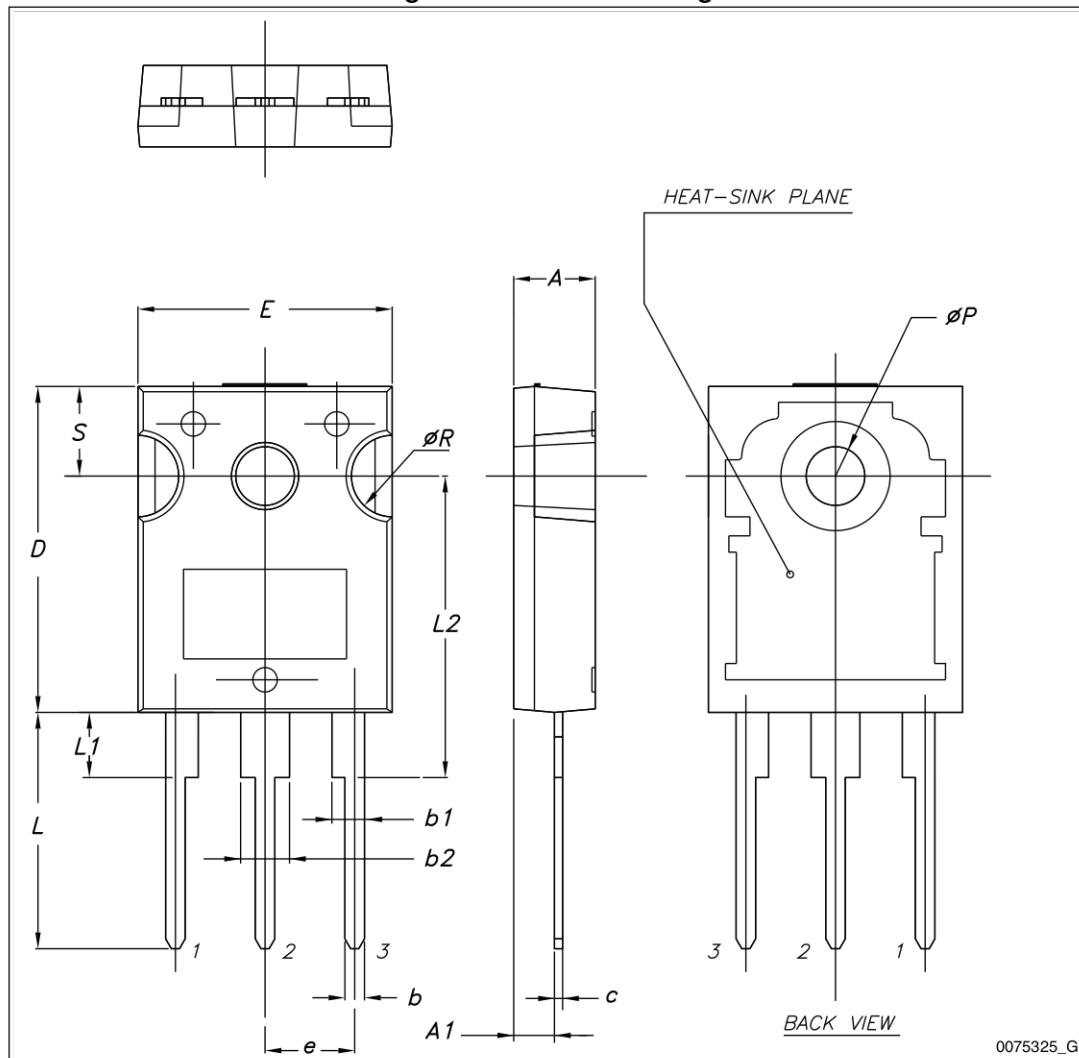
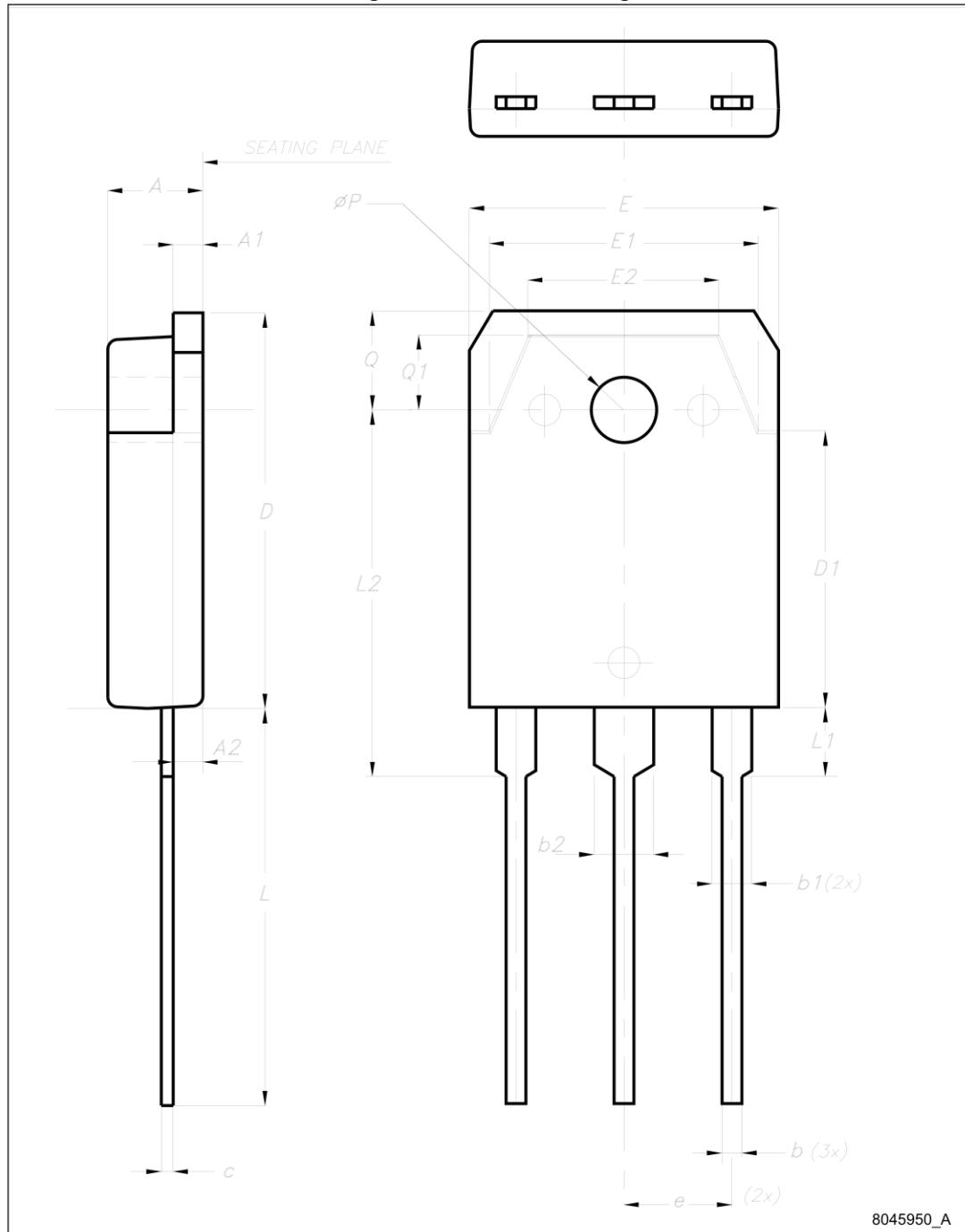


Table 9. TO-3P mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.60		5
A1	1.45	1.50	1.65
A2	1.20	1.40	1.60
b	0.80	1	1.20
b1	1.80		2.20
b2	2.80		3.20
c	0.55	0.60	0.75
D	19.70	19.90	20.10
D1		13.90	
E	15.40		15.80
E1		13.60	
E2		9.60	
e	5.15	5.45	5.75
L	19.50	20	20.50
L1		3.50	
L2	18.20	18.40	18.60
øP	3.10		3.30
Q		5	
Q1		3.80	

Figure 31. TO-3P drawing



5 Revision history

Table 10. Document revision history

Date	Revision	Changes
07-Feb-2013	1	Initial release.
17-Jun-2013	2	Document status promoted from preliminary to production data.
01-Jul-2013	3	Updated Section 2.1: Electrical characteristics (curves) and Section Table 7.: IGBT switching characteristics (capacitive load)

Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

ST PRODUCTS ARE NOT AUTHORIZED FOR USE IN WEAPONS. NOR ARE ST PRODUCTS DESIGNED OR AUTHORIZED FOR USE IN: (A) SAFETY CRITICAL APPLICATIONS SUCH AS LIFE SUPPORTING, ACTIVE IMPLANTED DEVICES OR SYSTEMS WITH PRODUCT FUNCTIONAL SAFETY REQUIREMENTS; (B) AERONAUTIC APPLICATIONS; (C) AUTOMOTIVE APPLICATIONS OR ENVIRONMENTS, AND/OR (D) AEROSPACE APPLICATIONS OR ENVIRONMENTS. WHERE ST PRODUCTS ARE NOT DESIGNED FOR SUCH USE, THE PURCHASER SHALL USE PRODUCTS AT PURCHASER'S SOLE RISK, EVEN IF ST HAS BEEN INFORMED IN WRITING OF SUCH USAGE, UNLESS A PRODUCT IS EXPRESSLY DESIGNATED BY ST AS BEING INTENDED FOR "AUTOMOTIVE, AUTOMOTIVE SAFETY OR MEDICAL" INDUSTRY DOMAINS ACCORDING TO ST PRODUCT DESIGN SPECIFICATIONS. PRODUCTS FORMALLY ESCC, QML OR JAN QUALIFIED ARE DEEMED SUITABLE FOR USE IN AEROSPACE BY THE CORRESPONDING GOVERNMENTAL AGENCY.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2013 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Philippines - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com

